

**Search Notes**

Application/Control No.

10/005,193

Examiner

Fred I. Ehichioya

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2162

**SEARCHED**

Class	Subclass	Date	Examiner
707	1, 2, 3, 5, 101, 104.1	6/11/2005	FE
703	27	6/11/2005	FE
706	23	6/11/2005	FE
709	203, 223	6/11/2005	FE
713	176	6/11/2005	FE

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Search	6/11/2005	FE
IEEE Xplore Search	6/11/2005	FE
ACM Digital Library Search	6/11/2005	FE